


<b>Search Notes</b>  	<b>Application/Control No.</b>  10807188	<b>Applicant(s)/Patent Under Reexamination</b>  IKEDA ET AL.
	<b>Examiner</b>  Chawan, Sheela C	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	145,242	1/7/07	SCC
702	159	1/7/07	SCC
249	16,102,104,140,16,35,55,99,193,192	1/7/07	SCC
451	464,466,469,490	1/7/07	SCC
700	182,187,	1/7/07	SCC
264	225,254,256,35,34,338.33,316,259,255,245	1/7/07	SCC
156	304.5	1/7/07	SCC
382	166,178,190,199,203,241,255,266,300, 305. CCLS. US-PATENT ONLY , SEE TEXT SEARCH.	9/22/07	SCC
382	241, 199	9/22/07	SCC
700	187	9/22/07	SCC
ABOVE SEARCH UP-DATE		9/22/07	SCC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST, US-PGPUB,USPAT,EPO,JPO,DERWENT,IBM-TDB.	1/7/07	SCC
INVENTOR NAME SEARCH.	1/7/07	SCC
382/145,144,166,178,190,199,203,241,255,266,300,305.CCLS. US-PATENT ONLY SEE TEXT SEARCH.	9/22/07	SCC
700/187, 182.CCLS. " "	9/22/07	SCC
INTERFERENCE SEARCH , SEE SEARCH HISTORY PRINT OUT.	9/22/07	SCC
CONSULTED WITH SAMIR AHMED SPE 2624.	9/22/07	SCC
SEARCH INSPEC OR IEEE DATA BASE.	9/22/07	SCC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	145,241, 199	9/22/07	SCC
700	187	9/22/07	SCC